

FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			Attorney Docket No.: 19501-5 Applicant: John Hefti Filing Date: August 2, 1999		Application No.: 09/365,978 Group: 1643	
Reference Designation			U.S. PATENT DOCUMENTS		Page 1	
Examiner Initial	Document No.	Date	Name	Class	Sub-class	Filing Date (If Appropriate)
<u>W</u> AA	5,653,939	8/5/97	Hollis et al.		1	8/5/95
AB	5,846,708	12/8/98	Hollis et al.			4/23/92
AC	5,532,128	7/2/96	Eggers et al.			12/12/94
AD	5,846,842	12/8/98	Herron et al.			4/30/96
AE	5,827,482	10/27/98	Shieh et al.			8/20/96
AF	5,841,914	11/24/98	Shieh et al.			5/22/97
AG	5,846,843	12/8/98	Simon			11/18/96
AH	5,164,319	11/17/92	Hafeman et al.			11/17/89
AI	4,822,566	4/18/89	Newman			5/18/87
<u>V</u> AJ	5,156,810	10/20/92	Ribi			6/15/89
AK						
AL						
FOREIGN PATENT DOCUMENTS						
	Document No.	Date	Country	Class	Sub-class	Translation (Yes/No)
<u>W</u> AM	WO 97/41425	4/25/96	PCT International			No
<u>M</u> AN	WO 96/36871	11/21/96	PCT International			No
AO						
AP						
AQ						
AR						
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
<u>W</u> AS	Hollis et al., <u>A Swept Frequency Magnitude Method for the Dielectric Characterization of Chemical and Biological Systems</u> , IEEE Transactions on Microwave Theory and Techniques, Vol. MTT-28, No. 7, July 1980, pgs. 791-801.					
AT						
AU						
AV						
AW						
EXAMINER <u>W</u> DATE CONSIDERED <u>5/16/01</u>						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.